

N-Channel Power MOSFET

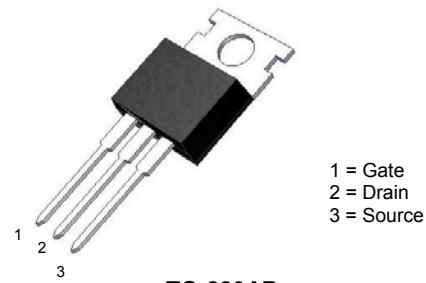
4.5A, 600V, 2.4Ω

General Description

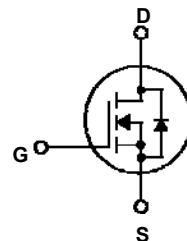
The N-Channel MOSFET is used an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance. This device is well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based half bridge topology.

Features

- Robust high voltage termination
- Avalanche energy specified
- Diode is characterized for use in bridge circuits
- Source to Drain diode recovery time comparable to a discrete fast recovery diode.



TO-220AB



DEVICE MARKING DESIGNATION:

Line 1 = TC Brand
Line 2 = Device Type

ABSOLUTE MAXIMUM RATINGS ($T_C=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Value	Units
V_{DSS}	Drain- Source Voltage	600	V
V_{GSS}	Gate-Source Voltage	± 30	V
I_D	Drain Current	4.5	A
I_{DM}	Drain Current Pulsed	18	A
P_D	Power Dissipation (Note 2)	100	W
	Derating factor above 25°C	0.8	W/ $^\circ\text{C}$
E_{AS}	Single Pulsed Avalanche Energy (Note 1)	216	mJ
E_{AR}	Repetitive Avalanche Energy (Note 2)	10	mJ
T_J	Operating Junction Temperature	150	$^\circ\text{C}$
T_{stg}	Storage Temperature Range	- 55 to +150	$^\circ\text{C}$

Notes:

1. $L=20\text{mH}$, $I_{AS}=4.5\text{A}$, $V_{DD}=50\text{V}$, $R_G=50\Omega$, Starting $T_J=25^\circ\text{C}$
2. Repetitive Rating: Pulse width limited by maximum junction temperature.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.26	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	$^\circ\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS
Off Characteristics ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	600	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 600V, V_{GS} = 0V$	--	--	10	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30V, V_{DS} = 0V$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30V, V_{DS} = 0V$	--	--	-100	nA

On Characteristics ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	--	4.0	V
$R_{DS(\text{ON})}$	On-Resistance	$V_{GS} = 10V, I_D = 2.25A$	--	1.9	2.4	Ω

Dynamic Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 1.0MHz$	--	592	737	pF
C_{oss}	Output Capacitance		--	55	75	pF
C_{rss}	Reverse Transfer Capacitance		--	13	16	pF

Switching Characteristics

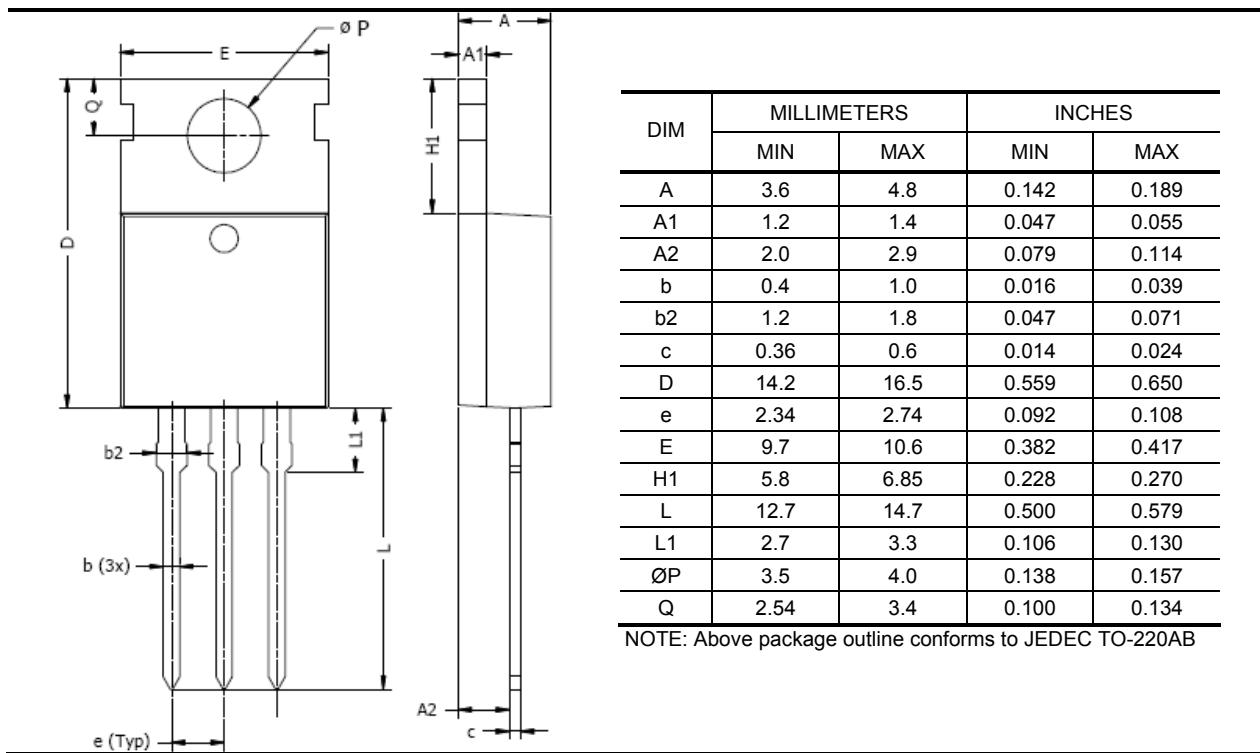
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 300V, I_D = 4.5A,$ $R_G = 25\Omega$ (Note 3 & 4)	--	12	34	nS
t_r	Turn-On Rise Time		--	45	100	nS
$t_{d(off)}$	Turn-Off Delay Time		--	40	90	nS
t_f	Turn-Off Fall Time		--	50	110	nS
Q_g	Total Gate Charge	$V_{DS} = 480V, I_D = 4.5A,$ $V_{GS} = 10V$ (Note 3 & 4)	--	19	28	nC
Q_{gs}	Gate-Source Charge		--	3	--	nC
Q_{gd}	Gate-Drain Charge		--	8	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	4.5	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	22	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0V, I_S = 4.5A$	--	--	1.5	V
T_{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_S = 4.5A,$ $dI_F / dt = 100A/\mu s$ (Note 3)	--	392	--	nS
Q_{rr}	Reverse Recovery Charge		--	1.57	--	μC

Notes:

3. Pulse Test: Pulse width < 300us, Duty cycle ≤ 2%.
4. Basically not affected by working temperature.

TO220AB PACKAGE OUTLINE




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